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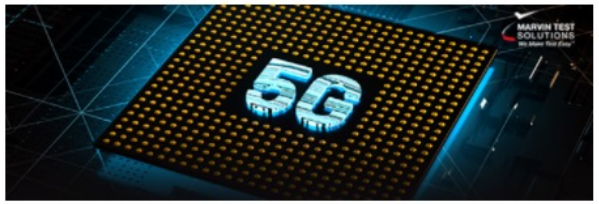
Overcoming 5G mmWave Semiconductor Production Test Challenges



Beamformer integrated circuits are the key to unlocking the low latency and increased bandwidth performance promised by 5G networks, and they play a critical role in other applications areas as well including radar, imaging and remote sensing.

Transitioning 5G mmWave semiconductor device test from the laboratory to the production floor poses significant challenges that encompass most areas of the test system including the instrumentation, cabling, interconnects, load board and calibration.

This paper will describe how selecting a MOSA (Modular Open System Architecture) based test system will ensure access to the latest instrumentation technology, including VNAs and dynamic digital instruments, simplify integration, and guard against obsolescence.

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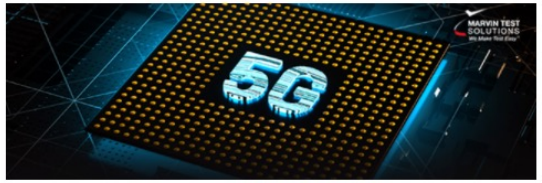
Transitioning 5G mmWave semiconductor device test from the laboratory to the production floor poses significant challenges that encompass most areas of the test system including the instrumentation, cabling, interconnects, load board and calibration. Achieving high throughput, without sacrificing measurement performance, requires a scalable multi-port instrumentation architecture capable of performing parallel test.

Selecting a MOSA-based (Modular Open System Architecture) test system will ensure access to the latest instrumentation technology, including VNAs and dynamic digital instruments, simplify integration, and guard against obsolescence. Marvin Test Solutions' TS-900e-5G 5G mmWave semiconductor test system delivers production proven performance, the fastest test times in the industry, and scalable multi-port operation to address evolving test needs.



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